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Response to Ex Parte Quayle Action

Serial No.: 09/865,612 Confirmation No.: 4697 Filed: May 25, 2001

For:

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SEMICONDUCTOR STRUCTURES

Amendments to the Claims

This listing of claims replaces all prior versions, and listings, of claims in the aboveidentified application:

Cancelled 1-17.

- 18. (Original) A chemical vapor deposition system comprising:
 - a deposition chamber having a substrate positioned therein;
 - a vessel containing a precursor comprising one or more complexes of the

formula:

 $[(R^1)NC(R^2)C(R^3)N(R^4)]_xML_y$

wherein:

M is a group IVB, VB, or VIB metal:

each R¹, R², R³, and R⁴ is independently H or an organic group;

L is selected from the group of CO, NO, CN, CS, CNR3, R6CN, or R7,

wherein each R5, R6, and R7 group is independently an organic group;

x = 1 to 4; and

y = 1 to 4; and

a source of inert carrier gas for transferring the precursor to the chemical vapor deposition chamber.

- 19. (Original) A chemical vapor deposition system comprising:
 - a deposition chamber having a substrate positioned therein;
 - a vessel containing a precursor composition comprising one or more complexes of the formula:

 $[(R^1)NC(R^2)C(R^3)N(R^4)]_xML_y$

wherein:

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M is a Group IVB, VB, or VIB metal; each R^1 , R^2 , R^3 , and R^4 is independently H or an organic group; each L is independently CO, NO, CN, CS, CNR⁵, R⁶CN, or R⁷, wherein cach R^5 , R^6 , and R^7 group is independently an organic group; x = 1 to 4; and y = 1 to 4.

- 20. (Currently Amended) The system of claim 38 [[19]] wherein the deposition chamber is adapted for forming a metal-containing film comprising vaporizing the precursor composition and directing it toward the semiconductor substrate or substrate assembly using a chemical vapor depositional technique.
- 21. (Original) The system of claim 20 wherein the chemical vapor deposition technique comprises flash vaporization, bubbling, microdroplet formation, or combinations thereof.
- 22. (Original) The system of claim 20 wherein the precursor composition is vaporized in the presence of a carrier gas.
- 23. (Original) The system of claim 20 wherein the precursor composition is vaporized in the presence of a reaction gas.
- 24. (Original) The system of claim 23 wherein the reaction gas is selected from the group of H₂, SiH₄, Si₂H₆, NH₃, N₂H₄, PH₂, AsH₃, GeH₄, t-BuSbMe₂, H₂S, H₂Se, Te(allyl)₂, and combinations thereof.
- 25. (Original) The system of claim 19 wherein each R¹, R², R³, and R⁴ group is independently H or a (C₁-C₃₀)organic group.

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- 26. (Original) The system of claim 19 wherein the complex is a monomer.
- (Original) The system of claim 19 wherein each R¹, R², R³, and R⁴ group is 27. independently H or a (C_1-C_4) alkyl moiety.
- (Original) The system of claim 19 wherein R7 is cyclopentadienyl or a substituted 28. cyclopentadienyl.
- **29**. (Original) The system of claim 19 wherein the precursor composition is a liquid.
- (Original) The system of claim 19 wherein the metal is a Group VB metal. 30.
- (Original) The system of claim 30 wherein the metal is vanadium. 31.
- (Currently Amended) The system of claim 20 [[19]] wherein the metal-containing film 32. is a Group IVB, VB, or VIB metal alloy film.
- 33. (Original) A chemical vapor deposition system comprising:
 - a deposition chamber having a semiconductor substrate or substrate assembly positioned therein;
 - a vessel containing a precursor composition comprising one or more complexes of the formula:

 $[(R^1)NC(R^2)C(R^3)N(R^4)]_xML_y$

wherein:

M is a Group IVB, VB, or VIB metal; each R¹, R², R³, and R⁴ is independently H or an organic group;

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each L is independently CO, NO, CN, CS, CNR⁵, R⁶CN, or R⁷, wherein each R⁵, R⁶, and R⁷ group is independently an organic group; x = 1 to 4; and y = 1 to 4.

- (Original) The system of claim 33 wherein each R¹, R², R³, and R⁴ is independently H or a (C₁-C₃₀)organic group.
- 35. (Original) The system of claim 33 wherein the complex is a monomer.
- 36. (Original) The system of claim 33 wherein each R¹, R², R³, and R⁴ group is independently H or a (C₁-C₄)alkyl moiety.
- 37. (Original) The system of claim 33 wherein R⁷ is cyclopentadienyl or a substituted cyclopentadienyl.
- 38. (Currently Amended) A chemical vapor deposition system comprising:

a deposition chamber having a semiconductor substrate or substrate assembly positional therein;

a vessel containing a precursor composition comprising one or more liquid complexes of the formula:

 $[(R^1)NC(R^2)C(R^3)N(R^4)]_xML_y$

wherein:

M is a Group IVB, VB, or VIB metal; each R¹, R², R³, and R⁴ independently H or a (C₁ - C₃₀)organic group; each L is independently CO, NO, CN, CS, CNR⁵, R⁶CN, or R⁷, wherein each R⁵, R⁶, and R⁷ group is independently an organic group;

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x = 1 to 4; and

y = 1 to 4.